Explore Circuit Behavior Using Simulation-Driven Instruments in NI Multisim

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Overview

NI Multisim software provides simulation-driven instruments that you can use to drive your circuit, measure the behavior of the circuit, and examine simulation results. These instruments are set, used, and read just like their real-world equivalents. This article examines the three different types of simulation-driven instruments and how you can use these instruments to drive circuits, make measurements, probe, and troubleshoot a circuit.

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1. Introduction to Simulation-Driven Instruments

In addition to the components and wires used to capture a circuit, NI Multisim software contains a variety of simulation-driven instruments that wire into the schematic just like you connect a real instrument on the bench. These simulation-driven instruments, like their real-world counterparts, are fully interactive so you can change their settings while running a simulation and instantly see new results.



Simulation-driven instruments help you take advantage of the full power of simulation without having to be an expert in SPICE syntax. When you press a button on an instrument, an appropriate simulation command is automatically issued and results are immediately displayed on that instrument's user interface. You can save instrument settings and simulation results with the circuit file and resize the faceplates of instruments to adjust to different screen resolutions and presentation modes.

With Multisim, you can place simulation-driven instruments from the Simulate»Instruments menu or directly from the Instruments toolbar as seen below.



Simulation-driven instruments have three distinctive views to each instrument, which allows for selection, placement, wiring, setting configuration, data visualization, and so on.

Туре	Description	View
lcon	Represents an instrument in the Multisim Instruments toolbar	<u>(3)</u>
Symbol	 Represents an instrument in a circuit Use the instrument's terminals to wire it to a circuit Double-click on an instrument's symbol to open the instrument panel 	+ - + •
Panel	Allows the user to interact with the instrument by	

- · Setting parameters
- Displaying data



You can show or hide the instrument panel by double-clicking on the instrument's symbol. The instrument panel is always drawn on top of the main workspace so that the parameters are not hidden. You can place the instrument panel wherever you wish on your desktop and resize it to account for different screen resolutions and presentation modes. When you save your circuit, the instrument panel location and hide/show status are stored with the circuit. Also, any data contained in the instrument is saved, up to a maximum size.

2. Types of Simulation-Driven Instruments

The three distinct types of simulation-driven instruments are Multisim instruments, LabVIEW custom VIs, and NI-ELVISmx instruments. All of these instruments offer the following key capabilities:

- Adjust settings while the simulation is running
- Rewire terminal while simulation is running
- · Use multiple instances of the same instrument in one circuit
- Save instrument settings and display data with the circuit file
- Populate displayed data in the Grapher view
- Resize instrument panel to account for screen resolution or presentation mode
- Easily export displayed data in TXT, LVM, and TDM format

3. Multisim Instruments

Multisim instruments are simulation-driven instruments that are innate in the Multisim environment. You can group them into six categories to better organize them:

- AC and DC instruments
- Digital and logic instruments
- RF instruments
- Simulated vendor instruments
- Measurement probes
- LabVIEW VIs

Note: Pictures and icons seen in this document are reduced in size and quality.

AC and DC Instruments

Name	Function	lcon	Symbol	Panel
Function Generator	 Sine, triangular, and square wave Frequency Duty cycle Amplitude Offset 			Image: Second secon
Multimeter	 AC and DC Current Voltage Resistance Decibel loss 			✓ Multimeter X ∑ 7.999 mA ▲ ▲ ∨ □ ▲ ∨ □ □ ↓ □ □ □ ↓ □ □ □ ↓ □ □ □ ↓ □ □ □ ↓ □ □ □ ↓ □ □ □ ↓ □ □ □
2-Channel Oscilloscope	 Up to 2 channels Y and X scaling Y offset Trigger Cursor 	*		
4-Channel Oscilloscope	 Up to 4 channels Y and X scaling Y offset Trigger Cursor 	****		
Wattmeter	Power measurementPower factor	₩ #	+V- +I- + - + -	

			✓ Wattmeter-X Image: Constant of the second se
IV Analyzer	 Diodes PNP BJT NPN BJT PMOS NMOS 		
Frequency Counter	 Frequency Period Pulse Rise/fall time AC or DC coupling Trigger 	123 φ	Frequences SIC1 SSIS2 SSIS2 Sources(not) more (not) SSIS2 Sources(not) Sour
Bode Plotter	 Frequency response Gain and phase shift Up to 10 GHz 		Main Main <t< th=""></t<>
Distortion Analyzer	 Intermodulation distortion Total harmonic distortion 	THD	Philoritise Analyzer -3DA2 Spat Miss Danise(1040) 28-575-03 Mass Danise(1040) Readminer # ng 1 2 Sile Nov Nov Nov Nov Nov Nov Nov Nov Nov

Digital and Logic Instruments

Name	Function	lcon	Symbol	Panel
Logic Analyzer	 16 channels Cursor Data history Trigger Internal/external clock 			
Logic Converter	 Digital circuit to truth table and Boolean expression Truth table to digital circuit Boolean expression to digital circuit 			
Word Generator	 Cycle, burst, and step updates Hex, DEC, Boolean, and ASCII data view Timing Trigger 			

RF Instruments

Name	Function	lcon	Symbol	Panel

Spectrum Analyzer	 Amplitude versus frequency Signal components (power and frequency) Zero, full, and custom span 		
Network Analyzer	 Digital circuit to truth table and Boolean expression Truth table to digital circuit Boolean expression to digital circuit 	28	

Simulated Vendor Instruments

Name	Function	lcon	Symbol	Panel
Agilent Waveform Generator	 Type: 33120A Reflects the behavior of the real instruments 	AG	Agilent	With Mandel Agend F Hart Nach Generation 2012 • Mandel Agend F Hart Nach Generation 2012 • Mandel Agend F Hart Nach Generation 2
Agilent DMM	 Type: 34401A Reflects the behavior of the real instruments 		Aglient Q G	Image: Application of the second of the s
Agilent Oscilloscope	 Type: 54622D Reflects the behavior of the real instruments 			
Tektronix Oscilloscope	 Type: TDS 2024 Reflects the behavior of the real instruments 			

Measurement Probes

Name	Function	Icon	Symbol	Panel
Static Measurement Probe	 Current, voltages, and frequency Referenced to circuit GND or any other probe Fixed to a net or at mouse cursor Triggers events Choose from: From dynamic probe setting AC voltage AC current Instantaneous voltage Voltage with reference to probe 	1.49		M(p-p): 1.00 ∨ M(ms): 707 m∨ M(p): 500 m∨ I(ms): 70.6 uA I(do): 49.9 uA Freq: 100 Hz M(p-p): 6.25 ∨ V(ms): 4.23 ∨ V(do): 2.99 ∨ I: -77.3 uA I(ms): 1.64 mA I(do): 99.7 uA Freq: 100 Hz
Current Probe				Use standard simulated instruments to display data



Ø,

Various voltage to current ratios



- Oscilloscope
- MultimeterAnd so on

Instruments Based on LabVIEW

Name	Function	lcon	Symbol	Panel
LabVIEW Microphone	 Interface with your PCs sound devices Recording length Sample rate 		Output	Terrepresent No.11
LabVIEW Speaker	 Interface with your PCs sound devices Update rate 	B	- Input	We standard tit 12 Print Barch and standard Little Named and standard Head and standard
LabVIEW Signal Analyzer	Time domain signalAuto power spectrumRunning average		Inl Multisin	
LabVIEW Signal Generator	 Sine, triangular, square, and sawtooth Frequency Duty cycle Amplitude Offset Phase 		Out1	
LabVIEW Streaming Signal Generator	 Sine, triangular, square, and sawtooth Frequency Duty cycle Amplitude Offset Phase Sampling rate 		Our.l	Weekendy Real Class IN 1911 Weekendy Real Class IN 1911
LabVIEW BJT Analyzer	 Current-voltage characteristics of PNP or NPN BJT Device type V_CE sweep I_B sweep 			
LabVIEW Impedance Meter	 Frequency sweep, frequency, impedance Number of points Scale type 	15 1		

4. LabVIEW Custom VIs

Extend your simulation and analysis capabilities beyond the instrumentation in Multisim with the creation of custom VIs using the LabVIEW graphical development environment. VIs that you create using LabVIEW can take advantage of the full functionality of the LabVIEW development system, including data acquisition, instrument control, and mathematical analysis. For example, you can create the following kinds of VIs:

- A virtual instrument that acquires data from the real world using a National Instruments data acquisition device or modular instrument. Multisim then uses that data as a signal source for circuit simulation.
- A virtual instrument that displays simulation data simultaneously with multiple measurements (running average and power spectrum, for example) made from that simulation data.

LabVIEW VIs can be input instruments, output instruments, or input/output instruments.

Input instruments receive simulation data for display or processing.

Output instruments generate data to use as a signal source in simulation.

Input/output instruments both receive and generate simulation data.

You can install these VIs created and customized in LabVIEW into Multisim, and they appear in the LabVIEW Instruments toolbar. For more information on building a LabVIEW VI and LabVIEW VI installation, view the Multisim Help file.

Download a sample LabVIEW custom VI to begin using them now»

5. NI-ELVISmx Instruments

By integrating NI ELVIS and Multisim, you can correlate simulated data with real-world measurements. NI Educational Laboratory Virtual Instrumentation Suite (NI ELVIS) is a National Instruments hardware design and prototyping platform that contains 12 of the most commonly used instruments into one integrated platform that connects to your computer through a Hi-Speed USB connection.

Inside the Multisim environment, you can access eight of these instruments. With one click of the mouse, you can switch from simulated data generated by the Multisim SPICE simulation engine and the signals acquired from the hardware. This helps engineers prototype faster and educators reinforce theory with real-world signals.

Name	Function	lcon	Symbol	Panel
NI-ELVISmx Digital Multimeter	 AC voltage AC current 			
NI-ELVISmx Function Generator	 Triangle, sine, square Up to 5 MHz Amplitude DC offset Sweep settings 			
NI-ELVISmx Oscilloscope	 2-channel, coupling, scale volt/div Time/div Trigger Acquisition mode cursors 		Elentro CHO CH1 TRS LTT TRS	
NI-ELVISmx Dynamic Signal Analyzer	 Power spectrum and power spectral density Frequency span, resolution, window Averaging mode, weight, number of averages Trigger Units and mode to display 			
NI-ELVISmx Digital Reader	Acquisition mode	66 01011		

NI-ELVISmx Digital Writer	 Pattern type Toggle, rotate, shift Generation mode Direction 	S ou		
NI ELVISmx Arbitrary Waveform Generator	 Waveform editor Generation mode Update rate Upload waveform file Set gain 		A00 A01	
NI-ELVISmx Variable Power Supply	 +12 V/-12 V range Sweep setting 	<u>K</u>		

6. Additional Resources

Download "How To" Examples for NI Multisim Virtual Instruments Download Instruments Based on LabVIEW Learn How to Create a LabVIEW VI for Multisim Visit the NI Circuit Design Technical Library Read about the Top Reasons to Adopt NI ELVIS